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| APPLICATION NO. | FILING DATE | FIRST NAMED INVENTOR | ATTORNEY DOCKET NO. | CONFIRMATION NO. |
|----------------------------|--|----------------------|---------------------|------------------|
| 10/525,296 | 02/15/2005 | Mayumi Uno | 10873.1606USWO | 6008 |
| | 7590 06/17/200 nnn, Mueller & Larson. | EXAMINER | | |
| P.O. Box 2902 | | VERDERAME, ANNA L | | |
| Minneapolis, MN 55402-0902 | | | ART UNIT | PAPER NUMBER |
| | | 1795 | | |
| | | | | |
| | | | MAIL DATE | DELIVERY MODE |
| | | | 06/17/2009 | PAPER |

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Advisory Action Before the Filing of an Appeal Brief

| Application No. | Applicant(s) | |
|-------------------|--------------|--|
| 10/525,296 | UNO ET AL. | |
| Examiner | Art Unit | |
| ANNA L. VERDERAME | 1795 | |

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| The MAILING DATE of this communication appe | ars on the cover sheet with the | correspondence add | ress |
| THE REPLY FILED <u>02 June 2009</u> FAILS TO PLACE THIS APP | | - | |
| The reply was filed after a final rejection, but prior to or on application, applicant must timely file one of the following rapplication in condition for allowance; (2) a Notice of Appe for Continued Examination (RCE) in compliance with 37 C periods: | the same day as filing a Notice of replies: (1) an amendment, affidavi al (with appeal fee) in compliance | Appeal. To avoid abar t, or other evidence, w with 37 CFR 41.31; or | hich places the (3) a Request |
| a) \boxtimes The period for reply expires <u>3</u> months from the mailing date | of the final rejection. | | |
| b) The period for reply expires on: (1) the mailing date of this Adno event, however, will the statutory period for reply expire la Examiner Note: If box 1 is checked, check either box (a) or (I MONTHS OF THE FINAL REJECTION. See MPEP 706.07(f | iter than SIX MONTHS from the mailin b). ONLY CHECK BOX (b) WHEN THE). | g date of the final rejection E FIRST REPLY WAS FII | on. LED WITHIN TWO |
| Extensions of time may be obtained under 37 CFR 1.136(a). The date of have been filed is the date for purposes of determining the period of extunder 37 CFR 1.17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked. Any reply received by the Office later may reduce any earned patent term adjustment. See 37 CFR 1.704(b). NOTICE OF APPEAL | ension and the corresponding amount hortened statutory period for reply original. | of the fee. The appropria nally set in the final Offic | ate extension fee e action; or (2) as |
| The Notice of Appeal was filed on A brief in compl filing the Notice of Appeal (37 CFR 41.37(a)), or any exter Notice of Appeal has been filed, any reply must be filed wi AMENDMENTS | sion thereof (37 CFR 41.37(e)), to | avoid dismissal of the | |
| | t mujay ta tha data of filing a byjaf | will not be entered be | |
| The proposed amendment(s) filed after a final rejection, be (a) They raise new issues that would require further cor (b) They raise the issue of new matter (see NOTE below | sideration and/or search (see NO w); | ΓE below); | |
| (c) They are not deemed to place the application in bett | er form for appeal by materially re | ducing or simplifying tl | ne issues for |
| appeal; and/or (d) ☐ They present additional claims without canceling a c NOTE: (See 37 CFR 1.116 and 41.33(a)). | orresponding number of finally rej | ected claims. | |
| 4. The amendments are not in compliance with 37 CFR 1.12 | 21. See attached Notice of Non-Co | mpliant Amendment (I | PTOL-324). |
| 5. Applicant's reply has overcome the following rejection(s): | | | , |
| Newly proposed or amended claim(s) would be allowed non-allowable claim(s). | | - | _ |
| 7. For purposes of appeal, the proposed amendment(s): a) [how the new or amended claims would be rejected is proved the status of the claim(s) is (or will be) as follows: | | ll be entered and an e | xplanation of |
| Claim(s) allowed: Claim(s) objected to: | | | |
| Claim(s) rejected: <u>1,3-7 and 10-17</u> . Claim(s) withdrawn from consideration: AFFIDAVIT OR OTHER EVIDENCE | | | |
| 8. ☐ The affidavit or other evidence filed after a final action, but | hefore or on the date of filing a No | ntice of Anneal will not | he entered |
| because applicant failed to provide a showing of good and was not earlier presented. See 37 CFR 1.116(e). | | | |
| 9. The affidavit or other evidence filed after the date of filing a entered because the affidavit or other evidence failed to or showing a good and sufficient reasons why it is necessary | vercome <u>all</u> rejections under appea and was not earlier presented. So | al and/or appellant fail ee 37 CFR 41.33(d)(1 | s to provide a). |
| 10. | n of the status of the claims after e | ntry is below or attach | ed. |
| 11. The request for reconsideration has been considered but See Continuation Sheet. | does NOT place the application in | condition for allowan | ce because: |
| 12. ☐ Note the attached Information <i>Disclosure Statement</i>(s). (13. ☐ Other: | PTO/SB/08) Paper No(s) | | |
| /Mark F. Huff/ | /Anna I Vardarama/ | | |
| Supervisory Patent Examiner, Art Unit 1795 | /Anna L Verderame/ Examiner, Art Unit 1795 | | |

Continuation of 11. does NOT place the application in condition for allowance because: In example 3 Kitaura et al. discloses a medium similar to applicant's medium 0 where all the recording layers have the same composition. The composition used in Kitaura et al. is Te42O53Pd5. Unlike for applicant's medium 0 the disc in example 3 has good optical charachteristics and acheives a high C/N ratio for each of the four recording layers. See section (0105) of Kitaura et al. Kitaura et al. has the same assignee as the instant application. The Kitaura et al. further discloses manipulating the recording layer compositions and discloses the effects observed when each component of the recording layer is adjusted. This is disclosed in sections (0040-0042) of Kitaura et al. The amounts of each component in the compositions taught Kitaura et al. Nishiuchi and applicant all fall within the ranges disclosed in Kitaura. Therefore Kitaura et al. discloses adjusting the amount of oxygen and Pd in the film and discloses the results that can be expected from doing so. The extinction coefficient and the refractive index of the resulting films will be an inherent property of the films formed(ephasis added).

Nishiuchi et al. discloses a Te-O-Pd composition that is diferent from that disclosed by Kitaura et al. However, the composition of Nishiuchi et al. falls witin the ranges disclosed for Te, O and Pd disclosed by Kitaura et al. Table 3 of Nishiuchi et al. discloses transmittance for the crystalline and amorphous phase for films having a composition of Te42O46Pd12, which is in the range dislosed in Kitaura et al. Examiner notes that the claims as written do not require that the transmittance of the films i adjusted by changing the thicknesses of the film and that transmittance can be adjusted in different ways such as adjusting the metal content of the film. Nishiuchi et al. also discloses adjusting the oxygen content and the effects of such adjustments in the experimental section.

The compositions in the examples taught in applicant's specification are different than those in the example of Kitaura et al. and different than that disclosed by Nishiuchi et al. In applicant's specification the media where all of the layers have the same composition performs poorly. However, in Kitaura et al. an almost identical medium ,where the composition of the reocrding layers is the same and the thicknesses are like those taught by applicant, performs well. Kitaura et al. and the instant application have the same assignee. It would help prosecution if applicant can show a one-to-one comparison between a medium like that taught by Kitaura et al., having the same recording layer compositions and thicknesses, and a medium where the oxygen content has been adjusted so that the oxygen in the closer recording layer is lower than that in further layers. The C/N ratios of each layer should be measured for this medium as well.